•	earch N	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/782,963	CHIU ET AL.	
Examiner	Art Unit	_
Kwasi Karikari	2617	

SEARCHED			
Class	Subclass	Date	Examiner
455	412.1	4/3/2006	K.K.
7	414.2	V	J.K
J	414.3		KK
	567	V	K-1C
	556.1		4.1

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
trigger\$4 with event with automat\$3	4/3/06	KK
	:	